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Analog 7335

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: Nevin et al.

GROUP: 2823

SERIAL NO: 10/699,503

EXAMINER: Hsien Ming Lee

FILED: 10/31/03

FOR: METHOD FOR FORMING A FILLED TRENCH IN A SEMICONDUCTOR LAYER OF A SEMICONDUCTOR SUBSTRATE, AND A SEMICONDUCTOR SUBSTRATE WITH A SEMICONDUCTOR LAYER HAVING A FILLED TRENCH THEREIN

Mail Stop Amendment

Commissioner of Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

In compliance with 37 C.F.R. §§1.56, 1.97, and 1.98, Applicant submits copies of the foreign documents listed on the attached Form PTO-1449.

The listed documents were recently cited in a related PCT application, and a copy of the International Search Report is being submitted herewith for purposes of convenience.

The Commissioner is authorized to charge Deposit Order Account No. 19-0079 for any further fee that is required.

Respectfully submitted,

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I hereby certify that this paper (along with any paper referred to as being attached or enclosed) is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to Mail Stop Amendment, Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450

Deborah M. Costello

40-17-05

Date

FORM PTO-1449  
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ATTORNEY DOCKET NO. 7335

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LeeOPI INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

JUN 20 2003

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	20010045614	11/29/01	Begley et al			4/1/99
AB	20020121673	9/5/02	Jono et al.			11/8/01
AC	20010023134	9/20/01	Akatsu et al.			3/31/98
AD	4,639,288	1/27/87	Price et al.			11/5/84
AE	4,656,730	4/14/87	Lynch et al.			11/23/84
AF	6,198,150	3/6/01	Gelzinis			3/6/01
AG	4,839,306	6/13/89	Wakamatsu			3/23/88
AH	6,627,514	9/30/03	Park et al.			11/10/00
AI						

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
AJ	0 048 175	9/16/81	EPO			Yes
AK						
AL						

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
AM		
AN		
AO		

EXAMINER

DATE CONSIDERED

EXAMINER:

Initial if citation considered, whether or not citation is in conformance with  
MPEP 609; draw line through citation if not in conformance and not  
considered. Include copy of this form with next communication to applicant.